

PHILIPS

sense and simplicity

A Manufacturer's Perspective on System Reliability for SSL products

J. Gaines, W. van Driel (Responsible for SSL Reliability)
Philips Lighting
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Topics

Where are we now with reliability?

What can we do better?

- Speed it up, with accelerated testing

- Make it more cost effective, by designing optimally

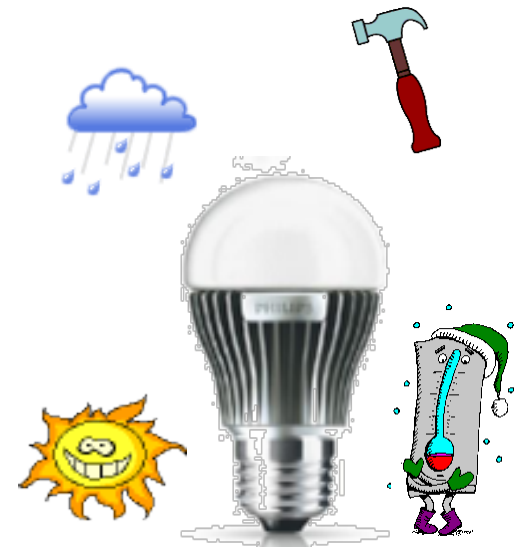
 - Avoid underdesign → premature failure

 - Avoid overdesign → cost higher than needed

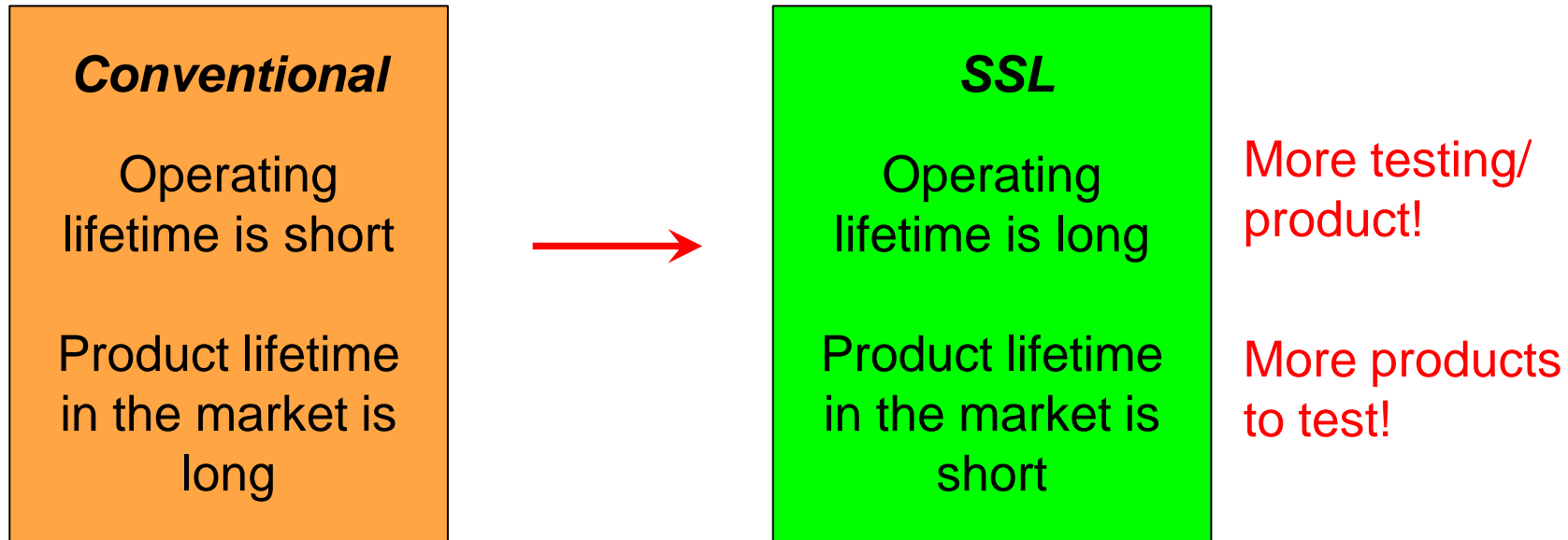
Reliability - Definition

Reliability - the probability that the equipment will perform its **intended function**, **under stated conditions**, for a **specified period of time** without failures

- What function should the equipment perform?
(E.g.: give light, dim, change color, ...)
- Under what application (use) conditions should the equipment function?
(e.g.: temp., humidity, vibration, ...)
- How long should the equipment last?
(e.g.: Technical or economical lifetime)

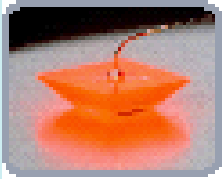
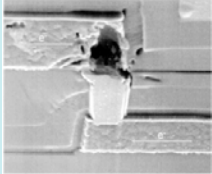
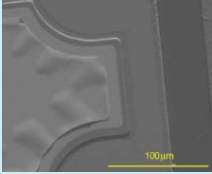







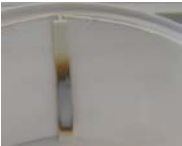







Lighting Transformation



So, we have to do a lot of work to ensure long lifetime, for a product we are only going to sell for a short time.

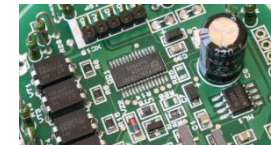
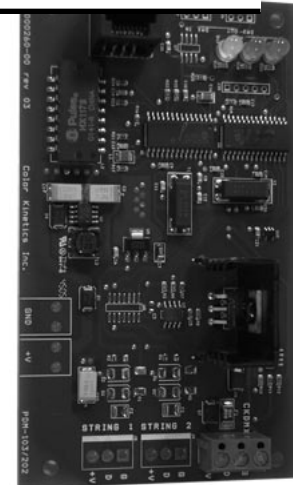
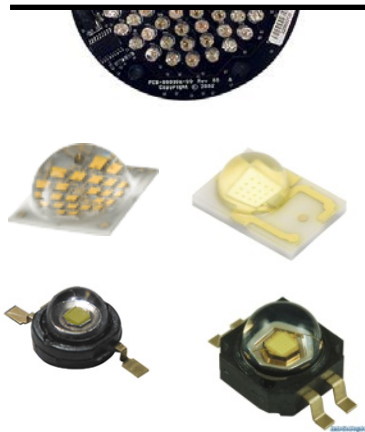
Identified Critical Failure Modes

Level		Identified Failure Modes
0: Bare Die		<ul style="list-style-type: none"> •LED catastrophic failure •Lumen depreciation (several causes) <ul style="list-style-type: none"> •Degradation of active region / ohmic contact •Electro-migration causing dislocations •Diffusion of metal atoms to the active region •Current crowding (uneven current distribution) •Doping related failures  
1: Packaged LED		<ul style="list-style-type: none"> •Yellowing of packaging materials (degradation/aging) •Electrostatic discharge (ESD) •Interconnect failure (solder or die-attach)   
2: LED sub-module		
3: LED module		<ul style="list-style-type: none"> •Casing cracks •Driver failures •Optic degradation (browning, cracks, reflection change) •ESD failures 
4: Luminaire		<ul style="list-style-type: none"> • Fractures (f.e. due to vibrations) • Moisture related failures (f.e. popcorning) •Corrosion due to water ingress •Deposition of outgassing material on the optics 
5: Lighting system		<ul style="list-style-type: none"> •Software failures •Electrical compatibility issues • Installation & commissioning issues  

Each FM has a certain ppm level, which we need to understand, minimize or solve & understand using reliability lifetime tests and analytical / numerical models

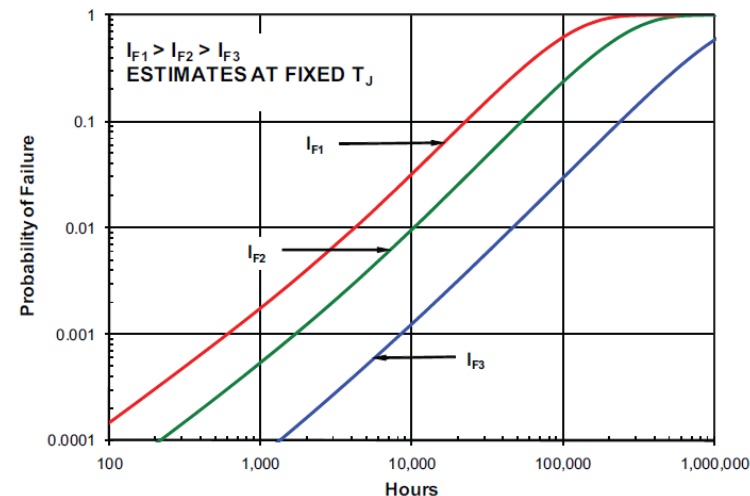
SSL products have 5 key-components

- 1 LED engine
- 2 Optics
- 3 Electronics
- 4 Cooling system
- 5 Mechanical construction



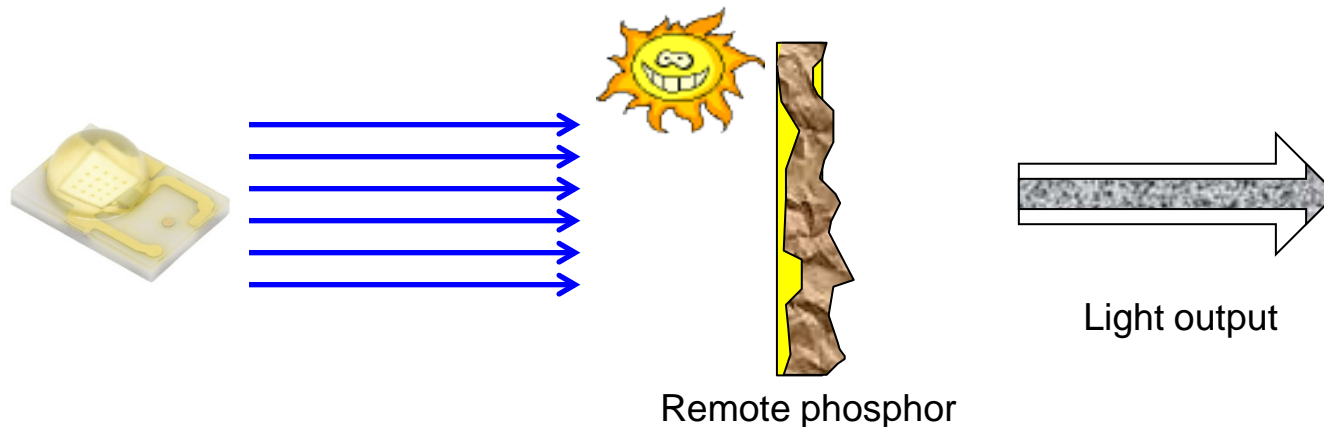
Experience-Based Approaches: Derating

- Basic principle: Same as your mother and father told you as a child: Treat your toys gently and they will last longer.
- Component manufacturers generally specify maximum temperatures, currents, etc → but life will be reduced.
- How gently do you have to treat it?
 - Depends on how long you want it to last.
- Based on experience with a component, we can come up with derating curves.
- But what if a new component comes along or a change is made to an existing component? Mature change management is needed.



Experience-Based Approaches: Derating

- Treat component A gently via derating
- Treat component B gently via derating
- But somehow, there is a problem when A and B are integrated. Interactions between the components (not foreseen) may create new failure mechanisms.



- There may be 100-200 components in an LED lamp/luminaire. Plenty of potential for unexpected interactions and failures.

Experience-Based Approaches: Stress Testing

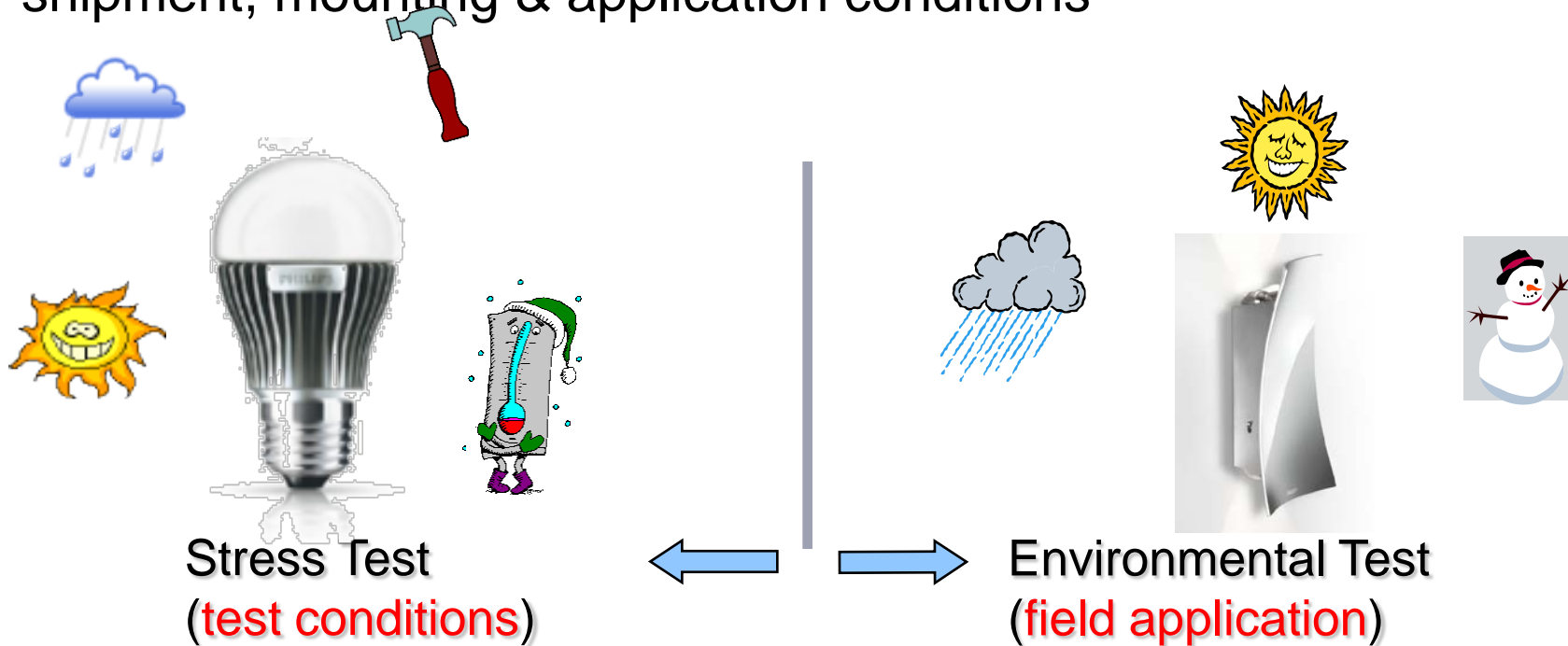
- During development, put products through a battery of tests, to see if they survive.
 - Extreme temperatures
 - High/low line voltage
 - Extreme humidity
 - Vibration
 - Different operating conditions (eg. On/off, vary CCT, dimming,...)
 - Chemical exposure (e.g. salt spray)
- But correlations between test results and product lifetime are experience-based “rules of thumb”.
- What if something changes?

System Reliability

- In principle: Component failure \neq System failure
- Each component in a system exhibits its own failure behavior
- This component failure behavior needs to be captured by:
 - Experiments by using at least 3 accelerated testing conditions
 - Numerical / analytical models that describe the *Physics of Failure*
- Interactions between the components need to be captured by:
 - Testing sub-systems
 - Testing the total system
 - By accelerating environmental user conditions in a physically correct manner

Acceleration

Experiment to assess the endurance of devices by “accelerating” shipment, mounting & application conditions



$$\text{Acceleration Factor} = \frac{\text{time to failure in application}}{\text{time to failure in test}}$$

Examples

Humidity Damp Heat



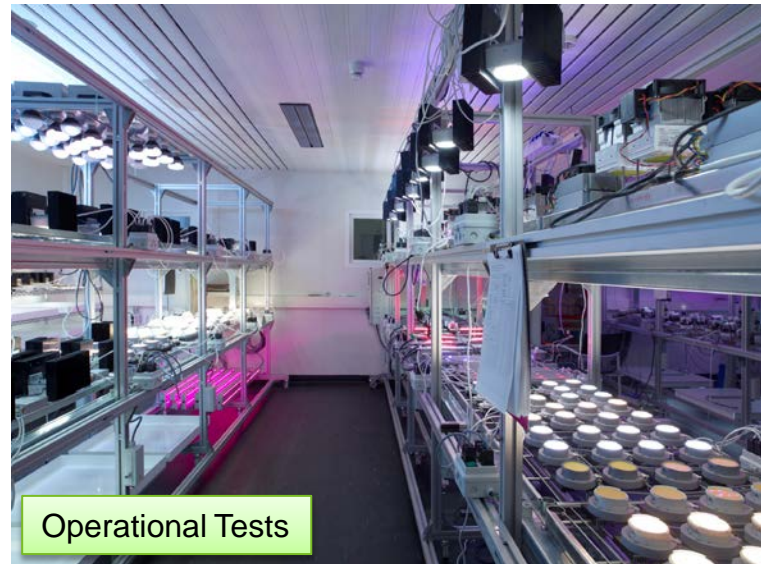
Highly Accelerated Life Test



Sleeve tests



Operational Tests



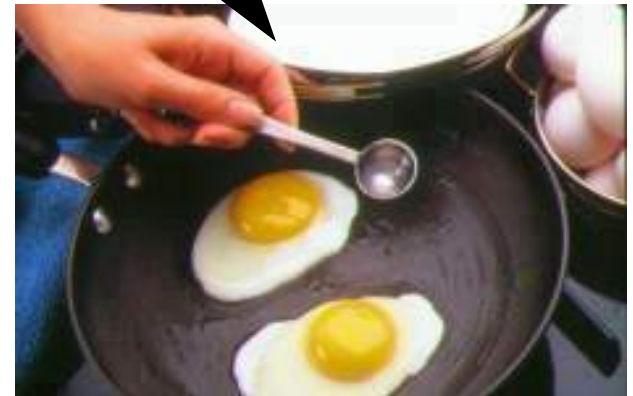
The risk of Blind Acceleration



21 days 37°C



3 minutes 140°C



Philips Approach for Reliability

- Combination of:
 - Derating rules (individual component basis)
 - Stress testing (many stresses)
 - Acceptable limits are set based on experience
 - Accelerated testing on sub-system level
 - Acceptable limits are set, based on understanding of physics of failure and acceleration factors
 - But there are many failure mechanisms. We have acceleration factors for our top 5 failure modes.
 - Verification testing on system level
 - System Reliability is based on Modeling → Predicted lifetime based on projected field call rates.

Needs

- Fundamental knowledge and industrial practices to understand the failure mechanisms. Both on component and system level.
- Fast, reliable and cost effective reliability qualification methods / procedures that allow coverage of the total product warranty period
- Acceleration factors (for each failure mechanism) to translate the accelerated test results to actual user conditions
- Multi-location efforts to determine the acceleration factors for each failure mechanism. Cooperate to share best practices and data.

